

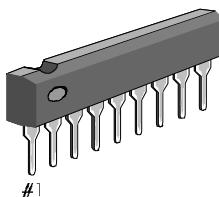
## INTRODUCTION

The S1A2220X01 is a monolithic integrated circuit consisting of a pre-amplifier and an ALC circuit for cassette tape recorders.

## FEATURES

- Low noise amplifier
- Wide operating supply voltage range  
 $V_{CC} = 3.5V - 14V$
- High output voltage
- Low distortion
- Wide ALC range
- Good ALC pair characteristic for stereo tape recorders

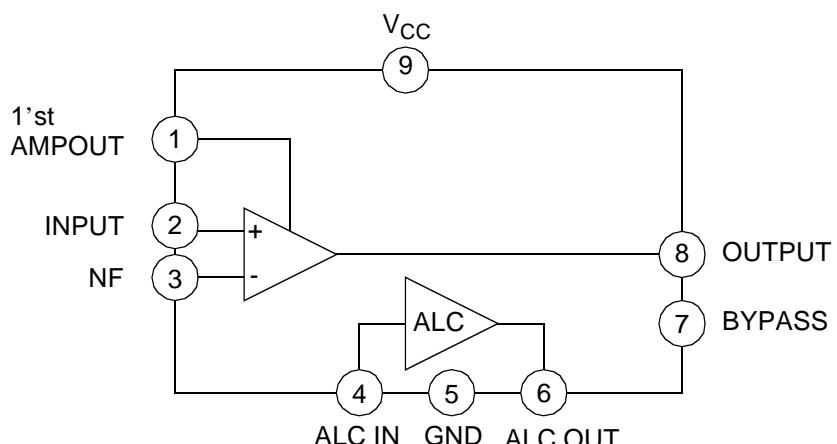
9-SIP



## ORDERING INFORMATION

Device	Package	Operating Temperature
S1A2220X01-IAU0	9-SIP	-20°C — +70°C
S1A2220X01-IBU0		

## BLOCK DIAGRAM

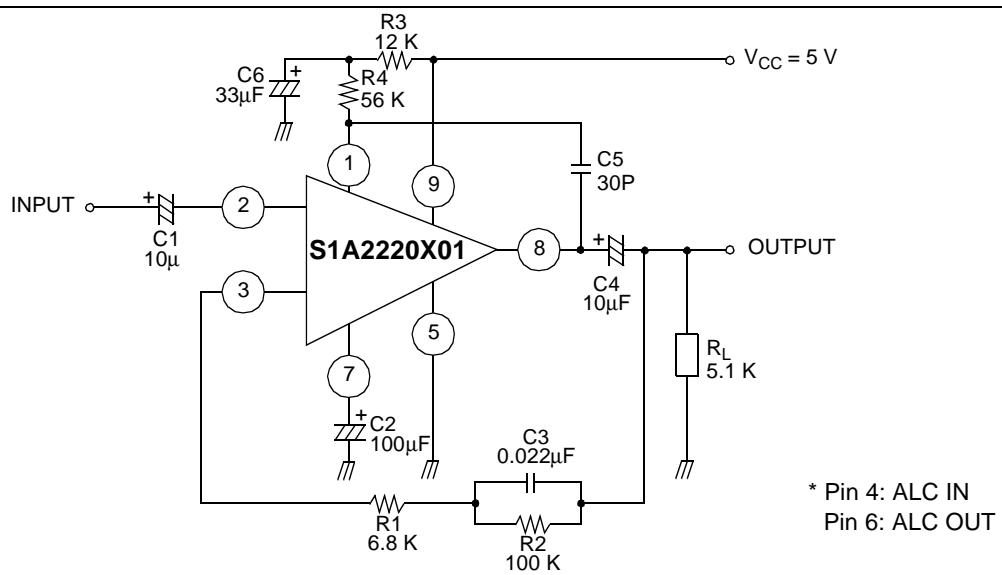


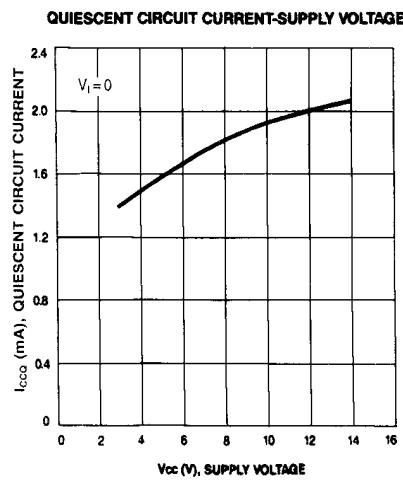
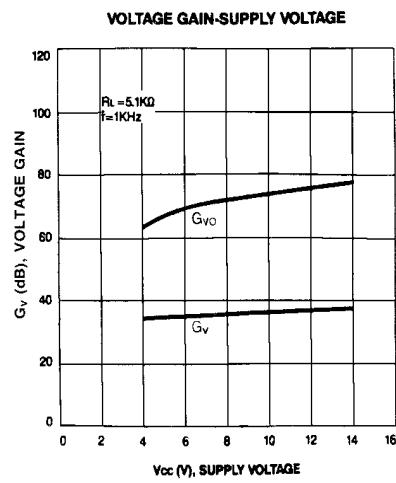
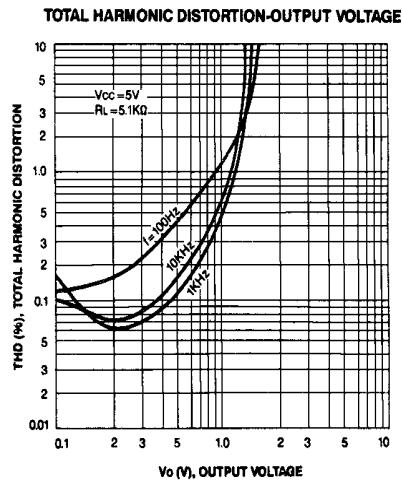
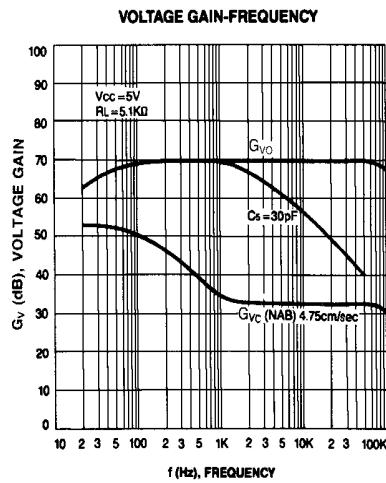
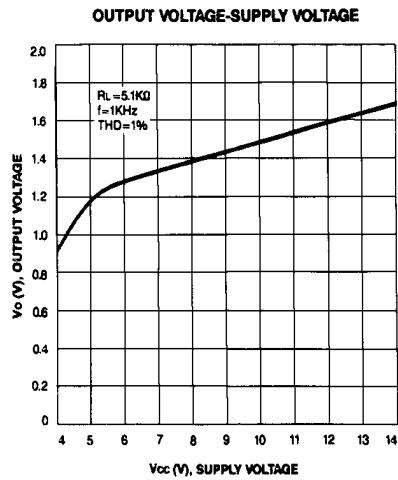
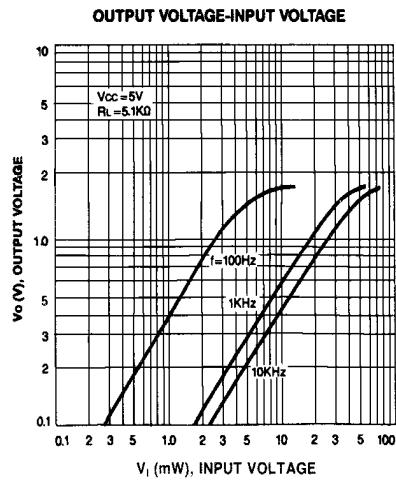
**ABSOLUTE MAXIMUM RATINGS (Ta = 25°C)**

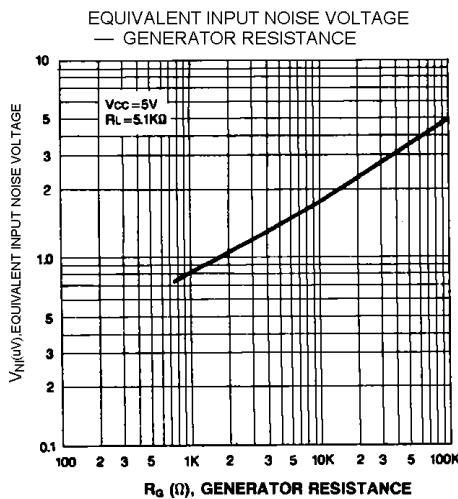
Characteristic	Symbol	Value	Unit
Supply voltage	V <sub>CC</sub>	15	V
Power dissipation	P <sub>D</sub>	200	mW
Operating temperature	T <sub>OPR</sub>	-20 — +70	°C
Storage temperature	T <sub>STG</sub>	-40 — +125	°C

**ELECTRICAL CHARACTERISTICS**(Ta = 25°C, V<sub>CC</sub> = 5V, R<sub>L</sub> = 5.1K, R<sub>G</sub> = 600Ω, f = 1kHz, NAB, unless otherwise specified)

Characteristic	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Quiescent Circuit Current	I <sub>CCQ</sub>	V <sub>I</sub> = 0, ALC OFF	—	1.4	2.0	mA
Open Loop Voltage Gain	G <sub>VO</sub>	—	66	69	—	dB
Closed Loop Voltage Gain	G <sub>VC</sub>	V <sub>O</sub> = 0.7 V	33	35	37	dB
Output Voltage	V <sub>O</sub>	THD = 1 %	0.7	1.0	—	V
Total Harmonic Distortion	THD	V <sub>O</sub> = 0.2 V	—	0.1	—	%
Input Resistance	R <sub>I</sub>	—	60	100	—	kΩ
Equivalent Input Noise Voltage	V <sub>NI</sub>	R <sub>G</sub> = 2.2kΩ, NAB BW (-3dB) = 15Hz – 30kHz	—	1.0	—	μV
ALC Transistor Saturation Voltage	V <sub>SAT</sub>	—	—	75	100	mV

**TEST CIRCUIT**





## APPLICATION INFORMATION

### ALC Grade Binning Table

Symbol	A <sub>V</sub> (dB)		ALC Grade (dB)	
	Min.	Max.	Min.	Max.
S1A2220X01-IAU0	34	36	-16.0	-27.0
S1A2220X01-IBU0			-25.0	-34.0

### External Components (Refer to test circuits)

C<sub>1</sub>: Input coupling capacitor

The recommended value is 10 μF. If made too small the low frequency characteristics will change for the worse, and too large a capacitance value will increase the rising time when power is applied.

C<sub>2</sub>: Bypass capacitor

A short emitter resistor on the AC, which prevents an AC signal from feedback from being input.

C<sub>3</sub>: R<sub>1</sub>, R<sub>2</sub>: Equalizer network

The closed loop voltage gain is determined by these components in relation to the internal resistance at Pin 3.

C<sub>4</sub>: Output coupling capacitor

C<sub>2</sub> is determined as follows:

$$C_4 = \frac{1}{2\pi \cdot f_L \cdot R_L}$$

f<sub>L</sub>: low cut-off frequency

R<sub>L</sub>: load resistance

C<sub>5</sub>: Phase compensation capacitor.

Prevents high frequency oscillation by phase error when feedback is heavy.

C<sub>6</sub>: Ripple filter for power supply

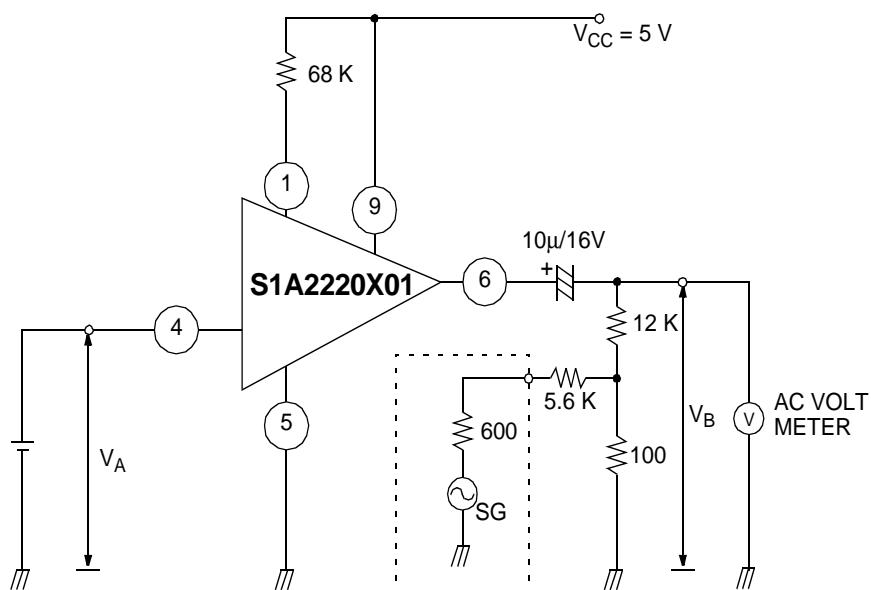
A large value is required to get an excellent ripple characteristic under the line operation, but it must be made smaller to shorten the starting time.

$R_3$ : Filter resistance

$R_4$ : Collector resistor of first stage transistor of the IC

Low voltage characteristic can be improved by adjusting this resistance.

## ALC GRADE BINNING TEST CIRCUIT



Test condition: S.G. output level should be adjusted to be 13.8 mV of the AC voltmeter reading ( $V_B$ ) when the D.U.T. is not connected to the test circuit ( $V_{CC} = 5V$ ,  $V_A = 1.16V$ ,  $T_a = 25^\circ C$ ).

ALC RANK is defined as  $ALC-G.R = 20 \log \frac{V_{B2}}{V_{B1}}$

where

$V_{B1}$ : AC voltmeter reading when the D.U.T. is not connected,

$V_{B2}$ : AC voltmeter reading when the D.U.T. is connected.

## APPLICATION CIRCUIT

